

## Test Report

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NXP SEMICONDUCTORS LTD.  
3F., NO. 19-8, SAN CHONG ROAD, NA GANG DISTRICT, TAIPEI 115, TAIWAN  
R. O. C.



The following sample(s) was/were submitted and identified by/on behalf of the client as :

Sample Description : HERMETICALLY SEALED GLASS (SURFACE-MOUNTED) PACKAGE  
SOD80C / SOD27 / SOD66 / SOD86 / SOD87  
Sample Receiving Date : 2012/02/27  
Testing Period : 2012/02/27 TO 2012/03/09

=====  
Test Result(s) : Please refer to next page(s).

**Chenyu Kung / Operation Manager**  
**Signed for and on behalf of**  
**SGS TAIWAN LTD.**  
**Chemical Laboratory – Taipei**

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## Test Result(s)

PART NAME NO.1 : BODY (CE/2009/27288 NO.1)

Test Item (s):	Unit	Method	MDL	Result
				No.1
Cadmium (Cd)	mg/kg	With reference to IEC 62321:2008 and performed by ICP-AES.	2	n.d.
Lead (Pb)	mg/kg	With reference to IEC 62321:2008 and performed by ICP-AES.	2	545000
Mercury (Hg)	mg/kg	With reference to IEC 62321:2008 and performed by ICP-AES.	2	n.d.
Hexavalent Chromium Cr(VI) by alkaline extraction	mg/kg	With reference to IEC 62321: 2008 and performed by UV-VIS.	2	n.d.
<b>Sum of PBBs</b>	mg/kg	With reference to IEC 62321: 2008 and performed by GC/MS.	-	n.d.
Monobromobiphenyl			5	n.d.
Dibromobiphenyl			5	n.d.
Tribromobiphenyl			5	n.d.
Tetrabromobiphenyl			5	n.d.
Pentabromobiphenyl			5	n.d.
Hexabromobiphenyl			5	n.d.
Heptabromobiphenyl			5	n.d.
Octabromobiphenyl			5	n.d.
Nonabromobiphenyl			5	n.d.
Decabromobiphenyl			5	n.d.
<b>Sum of PBDEs</b>			-	n.d.
Monobromodiphenyl ether			5	n.d.
Dibromodiphenyl ether			5	n.d.
Tribromodiphenyl ether			5	n.d.
Tetrabromodiphenyl ether			5	n.d.
Pentabromodiphenyl ether			5	n.d.
Hexabromodiphenyl ether			5	n.d.
Heptabromodiphenyl ether			5	n.d.
Octabromodiphenyl ether			5	n.d.
Nonabromodiphenyl ether			5	n.d.
Decabromodiphenyl ether			5	n.d.

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Test Item (s):	Unit	Method	MDL	Result
				No.1
<b>Halogen</b>		With reference to BS EN 14582:2007. Analysis was performed by IC method for F , Cl , Br, I content.		
Halogen-Fluorine (F) (CAS No.: 014762-94-8)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for Fluorine content.	50	n.d.
Halogen-Chlorine (Cl) (CAS No.: 022537-15-1)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for Chlorine content.	50	n.d.
Halogen-Bromine (Br) (CAS No.: 010097-32-2)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for Bromine content.	50	n.d.
Halogen-Iodine (I) (CAS No.: 014362-44-8)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for Iodine content.	50	n.d.

- Note :
1. mg/kg = ppm; 0.1wt% = 1000ppm
  2. n.d. = Not Detected
  3. MDL = Method Detection Limit
  4. " - " = Not Regulated

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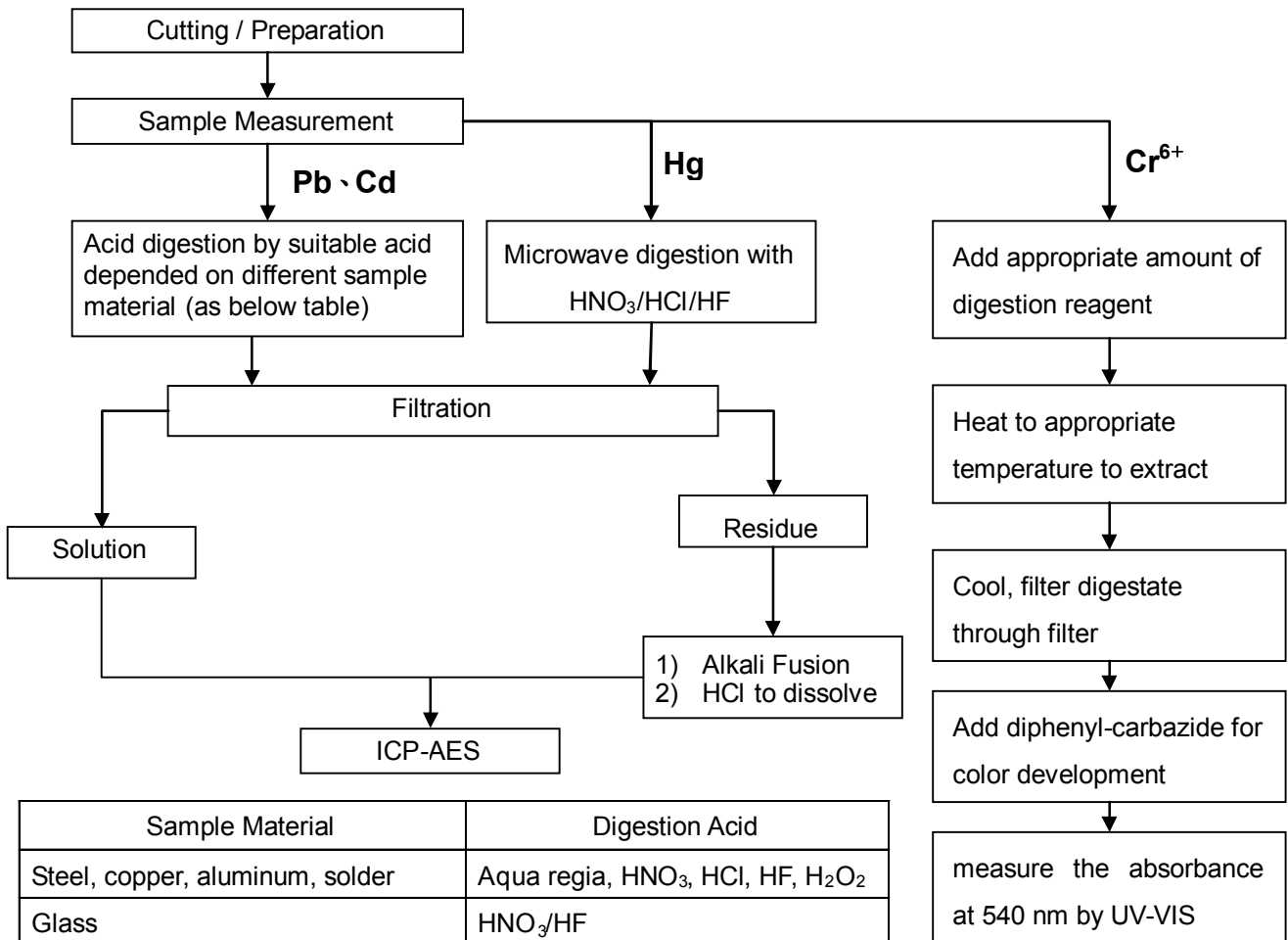
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- 1) These samples were dissolved totally by pre-conditioning method according to below flow chart.  
 ( Cr<sup>6+</sup> test method excluded )
- 2) Name of the person who made measurement: Climbgreat Yang
- 3) Name of the person in charge of measurement: Troy Chang



Sample Material	Digestion Acid
Steel, copper, aluminum, solder	Aqua regia, HNO <sub>3</sub> , HCl, HF, H <sub>2</sub> O <sub>2</sub>
Glass	HNO <sub>3</sub> /HF
Gold, platinum, palladium, ceramic	Aqua regia
Silver	HNO <sub>3</sub>
Plastic	H <sub>2</sub> SO <sub>4</sub> , H <sub>2</sub> O <sub>2</sub> , HNO <sub>3</sub> , HCl
Others	Any acid to total digestion

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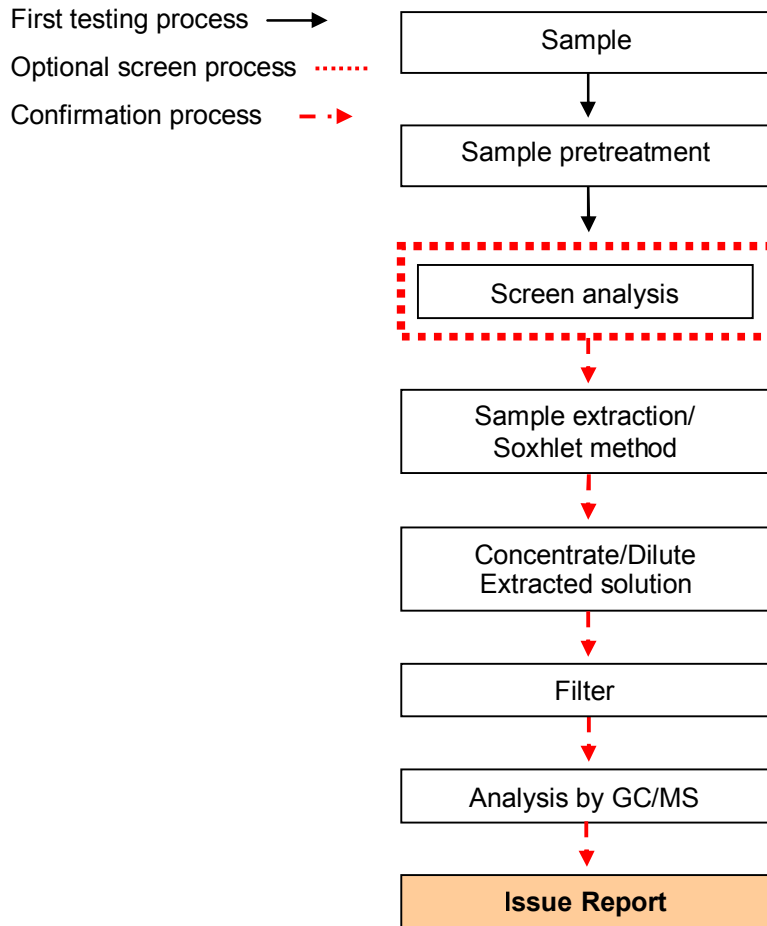
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### PBB/PBDE analytical FLOW CHART

- 1) Name of the person who made measurement: Roman Wong
- 2) Name of the person in charge of measurement: Shinjyh Chen



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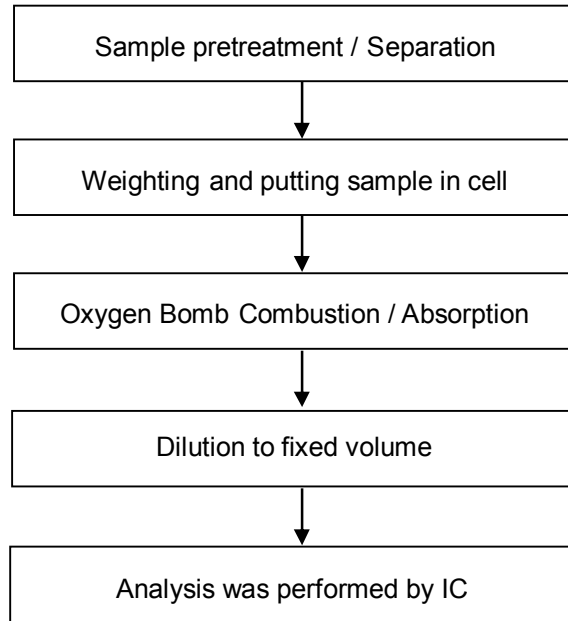
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### Analytical flow chart of halogen content

- 1) Name of the person who made measurement: Alan Chen
- 2) Name of the person in charge of measurement: Troy Chang



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\*\* End of Report \*\*

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